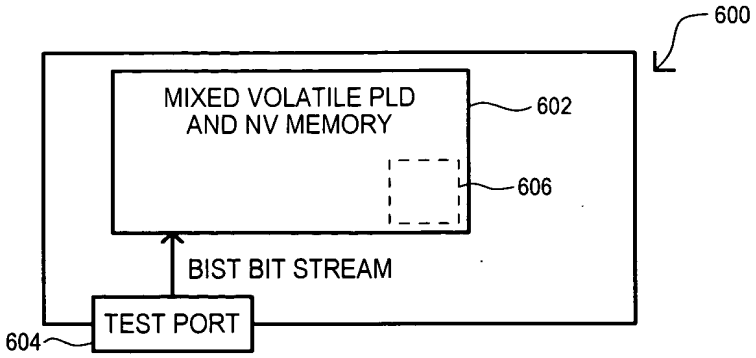

FIG. 6A

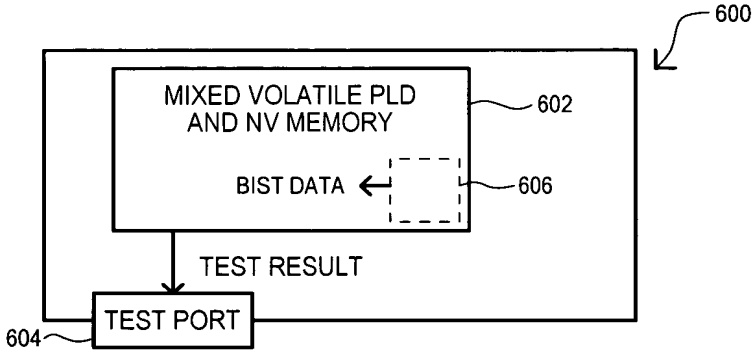

FIG. 6B

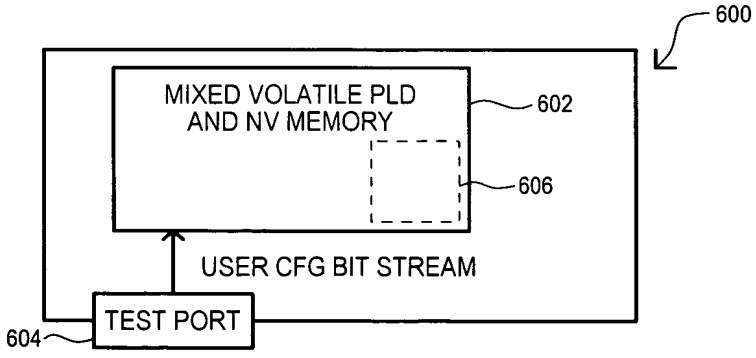

FIG. 6C

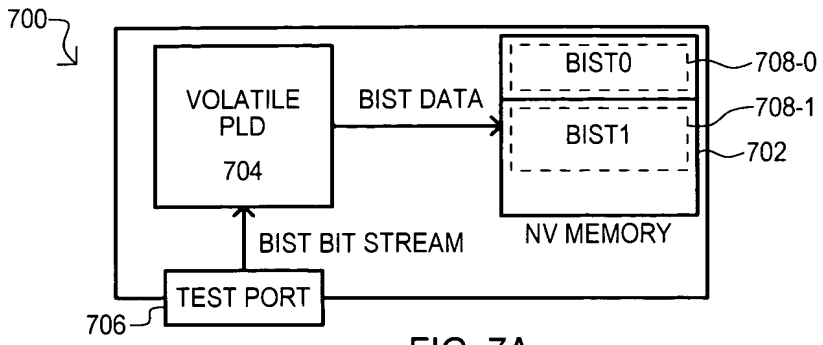

FIG. 7A

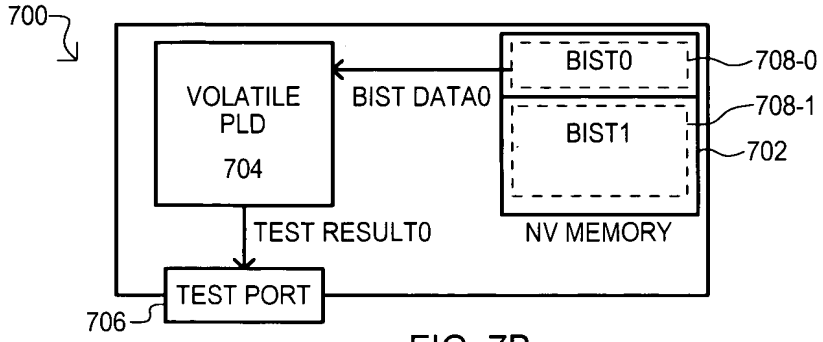

FIG. 7B

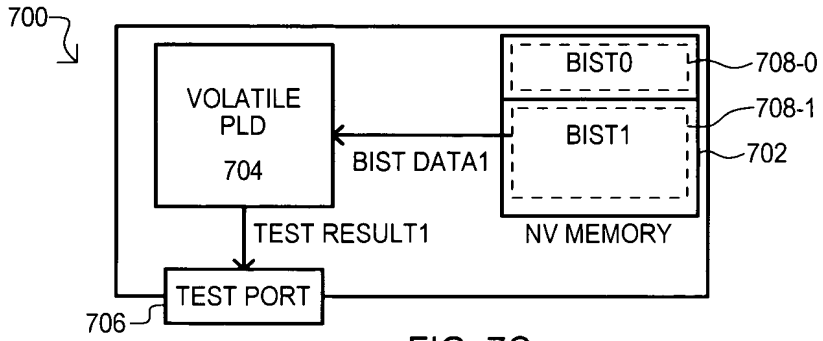

FIG. 7C

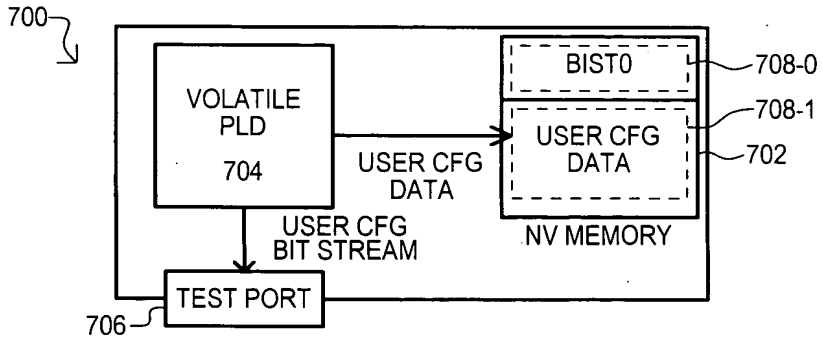

FIG. 7D

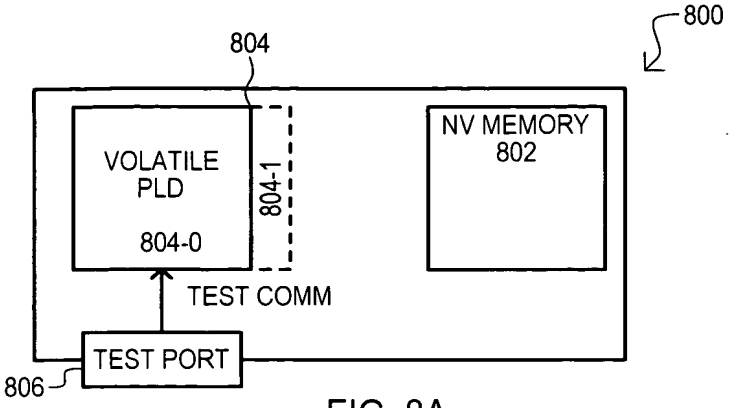

FIG. 8A

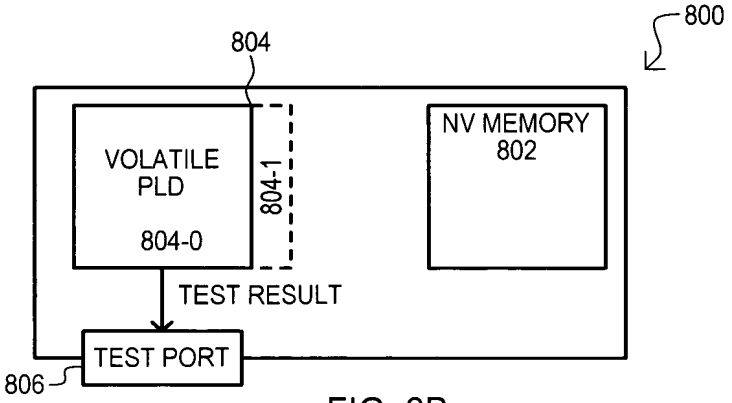

FIG. 8B

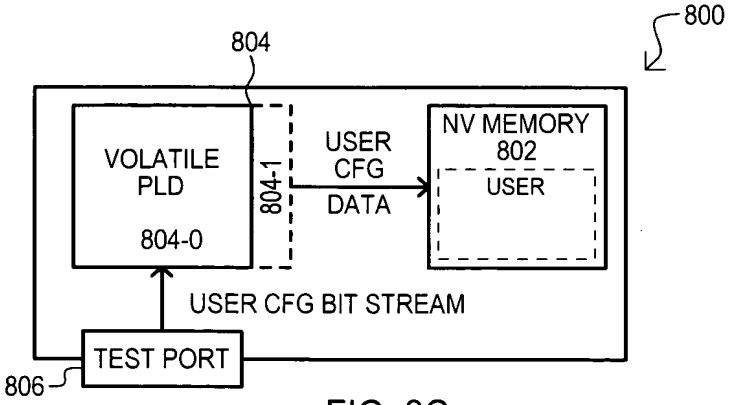

FIG. 8C

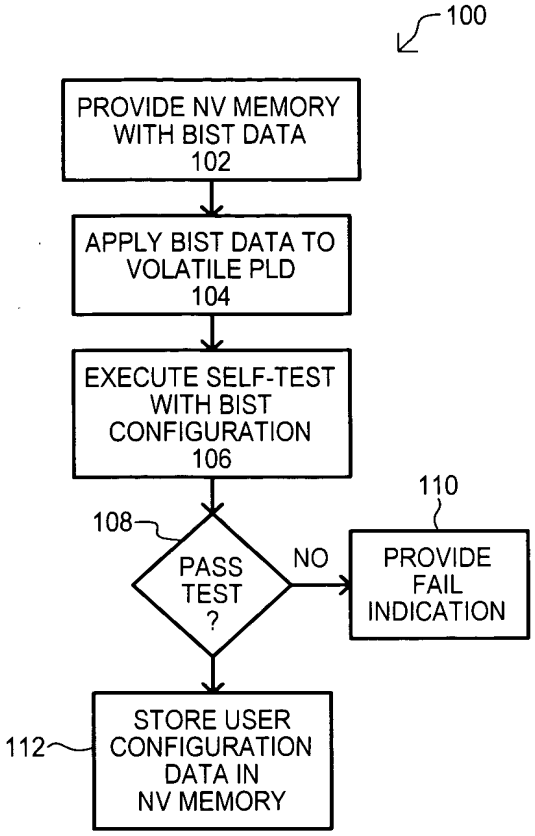
100
PROVIDE NV MEMORY WITH BIST DATA
102
APPLY BIST DATA TO VOLATILE PLD
104
EXECUTE SELF-TEST WITH BIST CONFIGURATION
106
108
PASS TEST ?
NO
110
PROVIDE FAIL INDICATION
112
STORE USER CONFIGURATION DATA IN NV MEMORY

FIG. 1

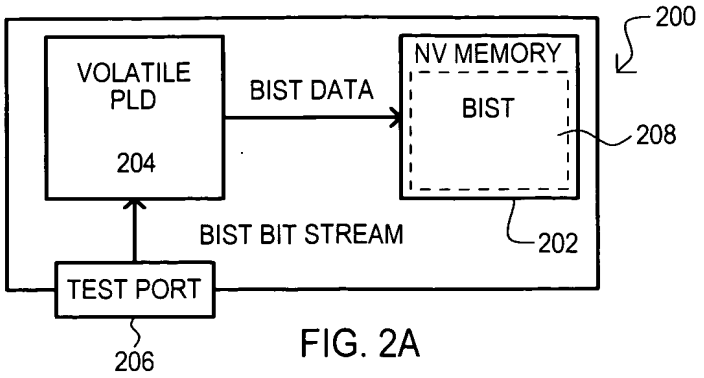

FIG. 2A

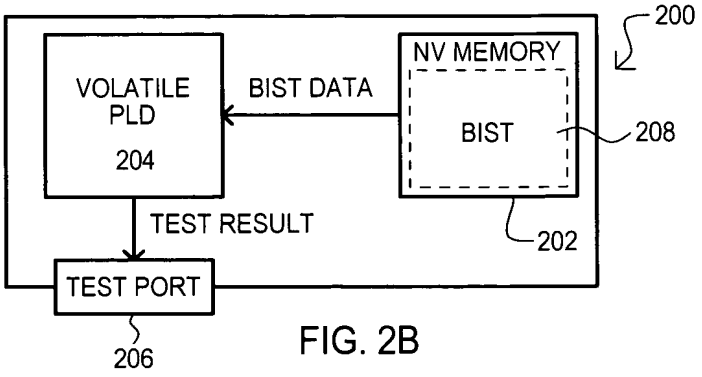

FIG. 2B

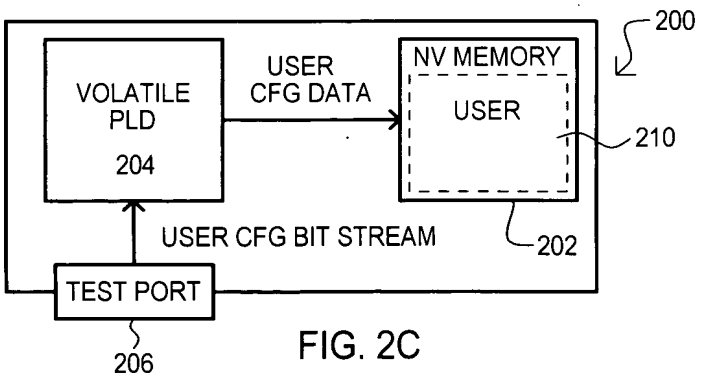

FIG. 2C

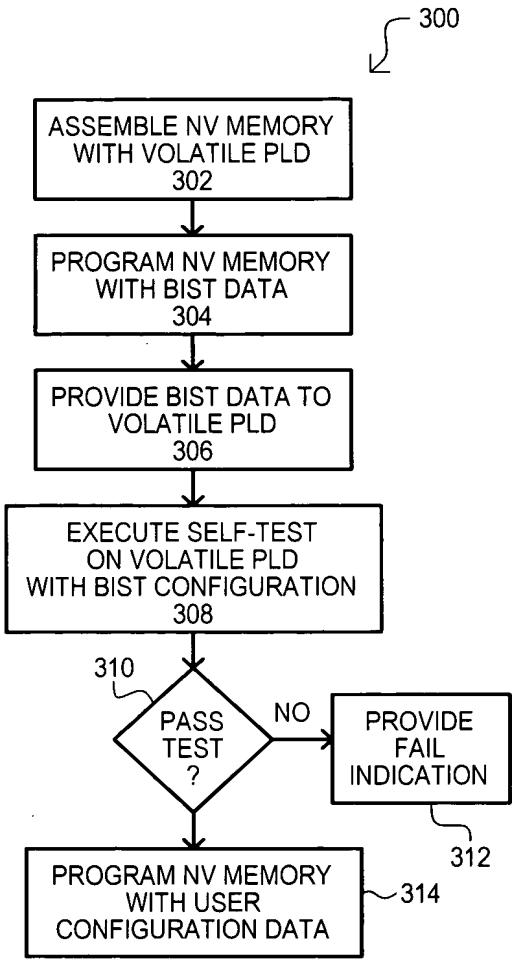
300
ASSEMBLE NV MEMORY WITH VOLATILE PLD
302
PROGRAM NV MEMORY WITH BIST DATA
304
PROVIDE BIST DATA TO VOLATILE PLD
306
EXECUTE SELF-TEST ON VOLATILE PLD WITH BIST CONFIGURATION
308
310
PASS TEST ?
NO
PROVIDE FAIL INDICATION
312
PROGRAM NV MEMORY WITH USER CONFIGURATION DATA
314

FIG. 3

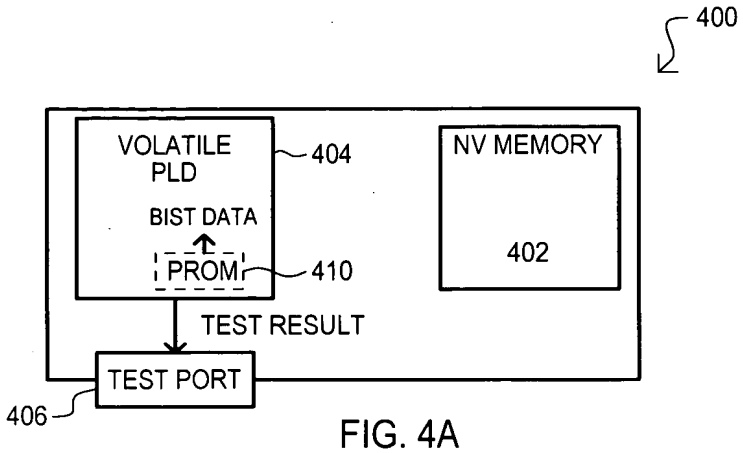
400
VOLATILE PLD
404
BIST DATA
PROM
410
NV MEMORY
402
TEST RESULT
TEST PORT
406

FIG. 4A

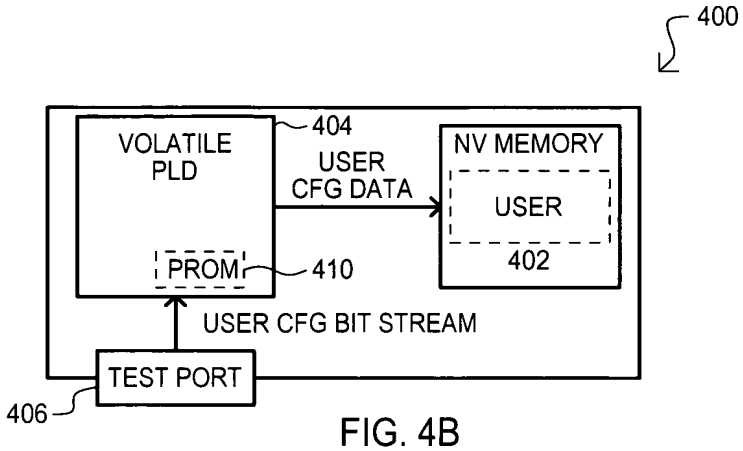
400
VOLATILE PLD
404
USER CFG DATA
NV MEMORY
USER
402
PROM
410
USER CFG BIT STREAM
TEST PORT
406

FIG. 4B

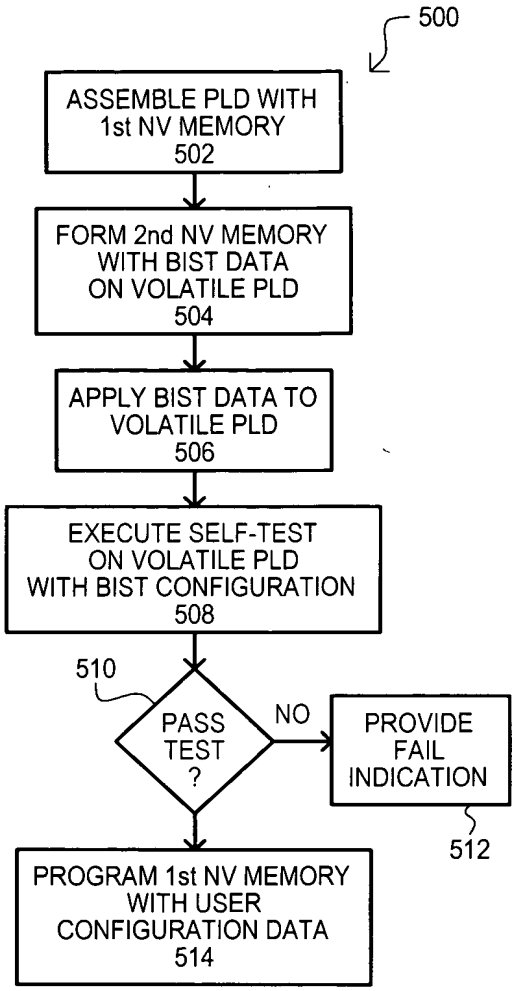
500
ASSEMBLE PLD WITH 1st NV MEMORY 502
FORM 2nd NV MEMORY WITH BIST DATA ON VOLATILE PLD 504
APPLY BIST DATA TO VOLATILE PLD 506
EXECUTE SELF-TEST ON VOLATILE PLD WITH BIST CONFIGURATION 508
510
PASS TEST ?
NO
PROVIDE FAIL INDICATION
512
PROGRAM 1st NV MEMORY WITH USER CONFIGURATION DATA 514

FIG. 5